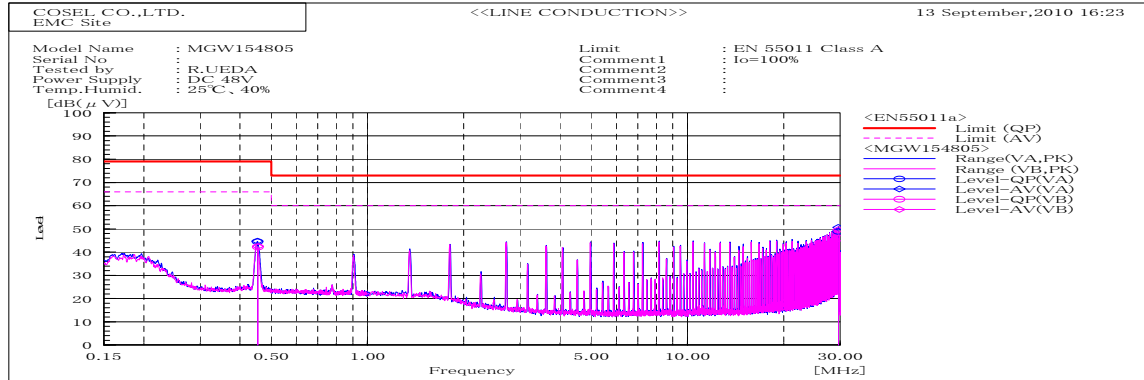
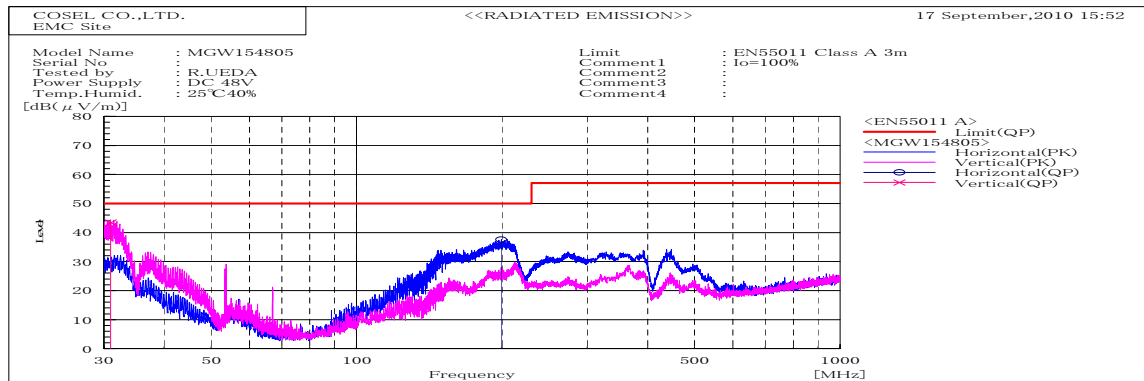


DATA SHEET		Date	21-Sep-10
Model	MGW154805	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Ueda



Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.45305		VA	34.4	34.6	10.1	44.5	44.7	79	66	34.5	21.3	Pass	
0.45478		VB	32.2	32.4	10	42.2	42.4	79	66	36.8	23.6	Pass	
29.60225		VB	34.9	38.7	11	45.9	49.7	73	60	27.1	10.3	Pass	
29.60505		VA	38.3	40	10.6	48.9	50.6	73	60	24.1	9.4	Pass	

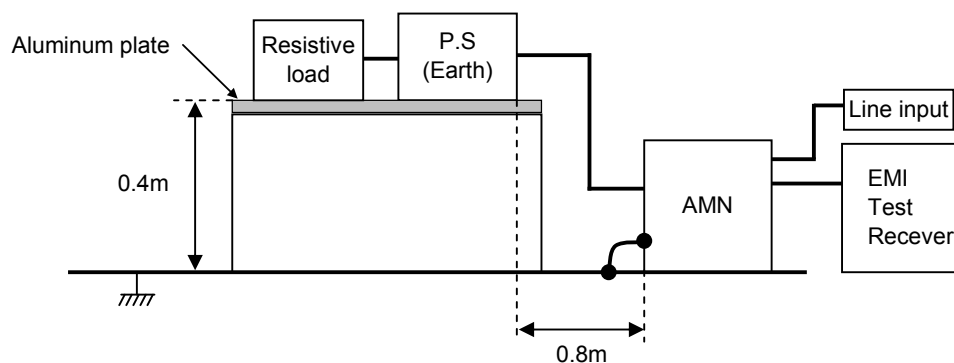


Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
31.008	V	Stable	57.4		-14	43.4		50	6.6	Pass	102	53	
199.037	H	Stable	59.6		-22	37.6		50	12.4	Pass	102	145	

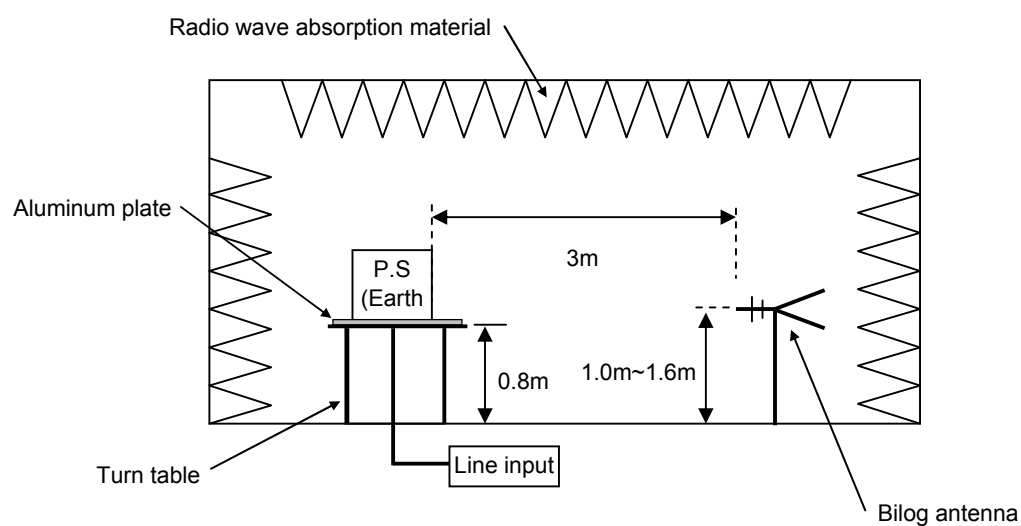
DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

1. Line conduction



2. Radiated emission



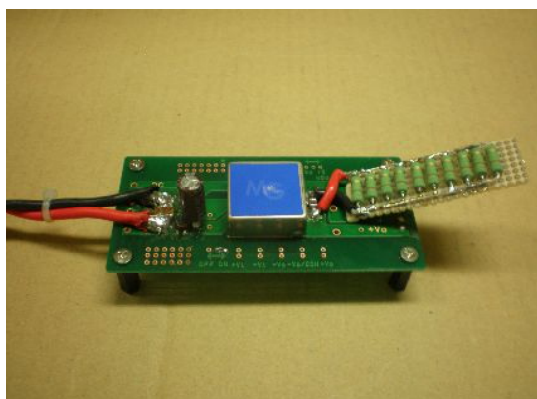


Conditions

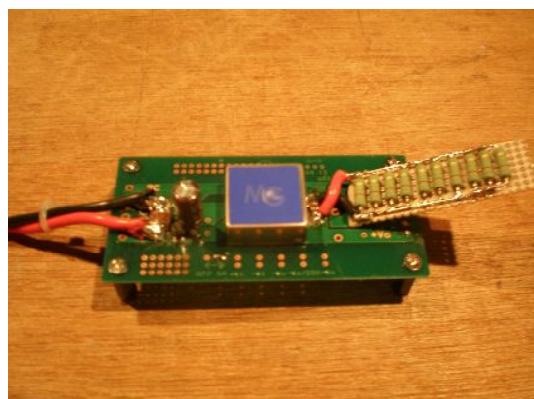
Test : EMI
Model Name : MGS1548□□/MGW1548□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

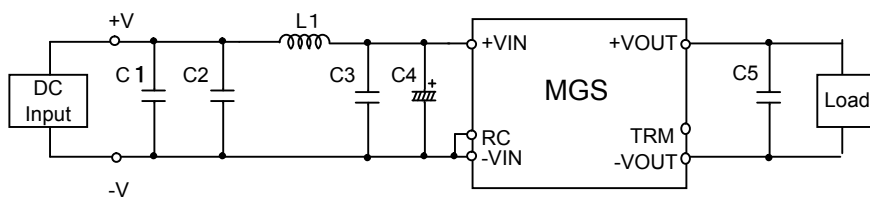


Fig.1 Testing circuitry 1

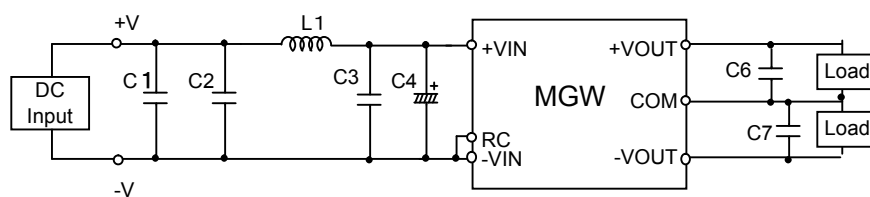


Fig.2 Testing circuitry 2

L1	: 10 μ H	CI4C-100	(KORIN ELECTRONICS)
C1,C2,C3	: 100V	2.2 μ F	C4532JB2A225MT (TDK)
C4	: 80V	47 μ F	LXV80VB47M (NIPPON CHEMI-CON)
C5,C6,C7	: 25V	22 μ F	CM32X5R226K25A (KYOCERA)